

Preliminary

SIDC53D120H6

Fast switching diode chip in EMCON-Technology

FEATURES:

- 1200V EMCON technology 120 μm chip
- soft, fast switching
- low reverse recovery charge
- small temperature coefficient

This chip is used for:

 EUPEC power modules and discrete devices



Applications:

 SMPS, resonant applications, drives

| Chip Type | V _R | l _F | Die Size | Package | Ordering Code |
|--------------|----------------|----------------|---------------------------|--------------|---------------|
| SIDC53D120H6 | 1200V | 100A | 7.3 x 7.3 mm ² | sawn on foil | Q67050-A4100 |

MECHANICAL PARAMETER:

| Raster size | 7.3 x 7.3 | | | | |
|---------------------------------|--|-----------------|--|--|--|
| Area total / active | 53.29 / 44.22 | mm ² | | | |
| Anode pad size | 6.58 x 6.58 | | | | |
| Thickness | 120 | μm | | | |
| Wafer size | 150 | mm | | | |
| Flat position | 180 | deg | | | |
| Max. possible chips per wafer | 304 pcs | | | | |
| Passivation frontside | Photoimide | | | | |
| Anode metallisation | 3200 nm AlSiCu | | | | |
| Cathode metallisation | 1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding | | | | |
| Die bond | electrically conductive glue or solder | | | | |
| Wire bond | AI, ≤500µm | | | | |
| Reject Ink Dot Size | Ø 0.65mm ; max 1.2mm | | | | |
| Recommended Storage Environment | store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C | | | | |



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Maximum Ratings

| Parameter | Symbol | Condition | Value | Unit |
|--|---------------------|-----------------------------------|---------|------|
| Repetitive peak reverse voltage | V _{RRM} | | 1200 | V |
| Continuous forward current limited by $T_{j\text{max}}$ | I _F | | 100 | |
| Single pulse forward current (depending on wire bond configuration) | I _{FSM} | t _P = 10 ms sinusoidal | tbd | A |
| Maximum repetitive forward current limited by T _{jmax} | I _{FRM} | | 200 | |
| Operating junction and storage temperature | T_{j} , T_{stg} | | -55+150 | °C |

Static Electrical Characteristics (tested on chip), $T_{j=25}$ °C, unless otherwise specified

| Parameter | Symbol | Cond | Value | | | Unit | |
|------------------------------------|-----------------|-----------------------|---------------------------|------|------|------|------|
| Falallelel | Symbol | Conditions | | min. | Тур. | max. | Onit |
| Reverse leakage current | I _R | V _R =1200V | <i>T_j=25°C</i> | | | 27 | μA |
| Cathode-Anode breakdown Voltage | V _{Br} | I _R =4mA | <i>T_j=25°C</i> | 1200 | | | V |
| Forward voltage drop | V _F | I _F =100A | <i>T_j=25°C</i> | | 1.6 | | V |

Dynamic Electrical Characteristics, at T_j = 25 °C, unless otherwise specified, tested at component

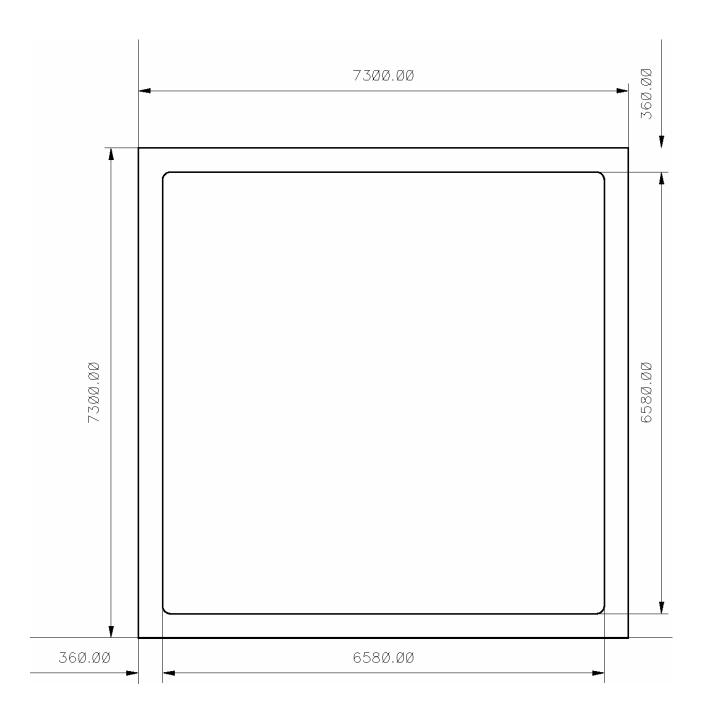
| Parameter | Symbol | Conditions | | Value | | | Unit |
|------------------------------|-----------------------|--|-------------------------------------|-------|-------|------|--------|
| | Symbol | | | min. | Тур. | max. | |
| Reverse recovery time | t _{rr1} | I _F =100A | $T_j = 25 \circ C$ | | tbd | | |
| | t _{rr2} | <i>di/dt=1100A/μs</i> <i>V_R=600V</i> | $T_j = 125 \circ C$ | | | | ns |
| Peak recovery current | I _{RRM1} | $I_{F}=100A$ | $T_j = 25 \circ C$ | | 119.8 | | А |
| | I _{RRM2} | di/dt=1100A/μs V _R = 600V | $T_j = 125 \circ C$ | | 127.5 | |]^ |
| Reverse recovery charge | Q _{rr1} | $I_{F}=100A$ | <i>T_j=25°C</i> | | 10 | | |
| | Q _{rr2} | di/dt=1100A/μs V _R = 600V | T _j =125°C | | 18 | | μC |
| Peak rate of fall of reverse | di _{rr1} /dt | I _F =100A | $T_{\rm j}$ = 25° C | | tbd | | • / |
| recovery current | di _{rr2} /dt | di/dt=1100A/µs V _R = 600V | T _j =125°C | | | | - A/μs |
| Softness | S1 | $I_{F}=100A$ | <i>T_j=25°C</i> | | tbd | | 4 |
| | S2 | di/dt=1100A/μs V _R = 600V | <i>T_j</i> =125° <i>C</i> | | | | |



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CHIP DRAWING:



Edited by INFINEON Technologies AI PS DD HV3, L 4392S, Edition 1, 8.01.2002



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FURTHER ELECTRICAL CHARACTERISTICS:

| This chip data sheet refers to the | INFINEON TECHNOLOGIES / | tbd |
|------------------------------------|-------------------------|-----|
| device data sheet | EUPEC | lbu |

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

Published by Infineon Technologies AG Bereich Kommunikation St.-Martin-Strasse 53 D-81541 München © Infineon Technologies AG 2000 All Rights Reserved.

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